



Shielded Button Measurement/ECLOUD Simulation Comparison for the Cloud Lifetime Study Using Witness Bunch Data

All material for this talk may be obtained at www.lepp.cornell.edu/~critten/cesrta/eccloud/24sep10

The measurements of 5/17/2010 are described here: <https://webdb.lepp.cornell.edu/elog/CTA+MS/629>

See also previous talks in the electron cloud meetings on simulations for the shielded button data on 4/21, 4/28, 5/12, 7/7, 7/14, 8/4, 9/8, 9/24/2010

Context

A primary purpose of the shielded pickup project (time-resolved measurements) is to measure the cloud lifetime. This lifetime is sensitive to the secondary yield for low-energy cloud particles hitting the vacuum chamber wall.

This presentation shows the first results on the sensitivity to the parameter δ_0 using witness bunch data.

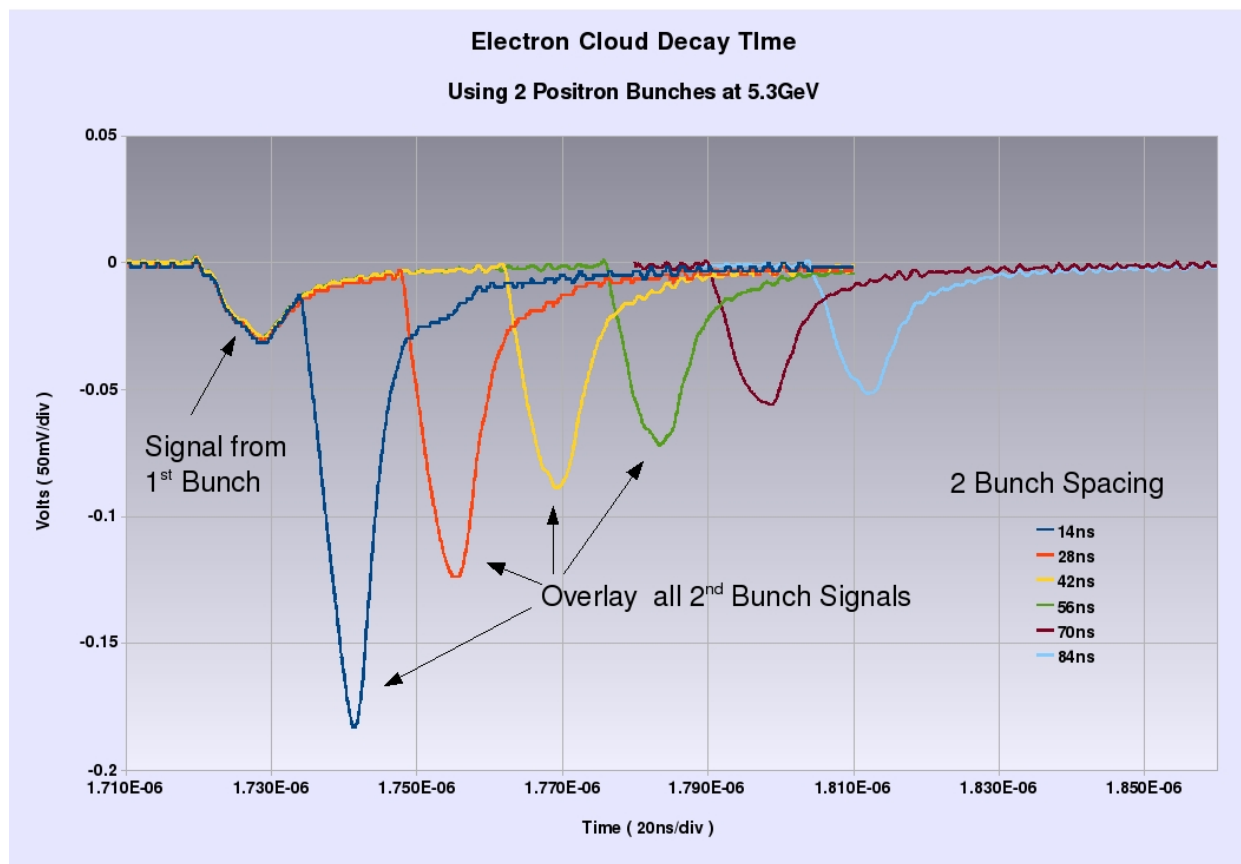
Jim Crittenden

Cornell Laboratory for Accelerator-Based Sciences and Education

CesrTA General Meeting

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https://cesrweb.lepp.cornell.edu/instr/data/shbut/2010/20100327_summary.html

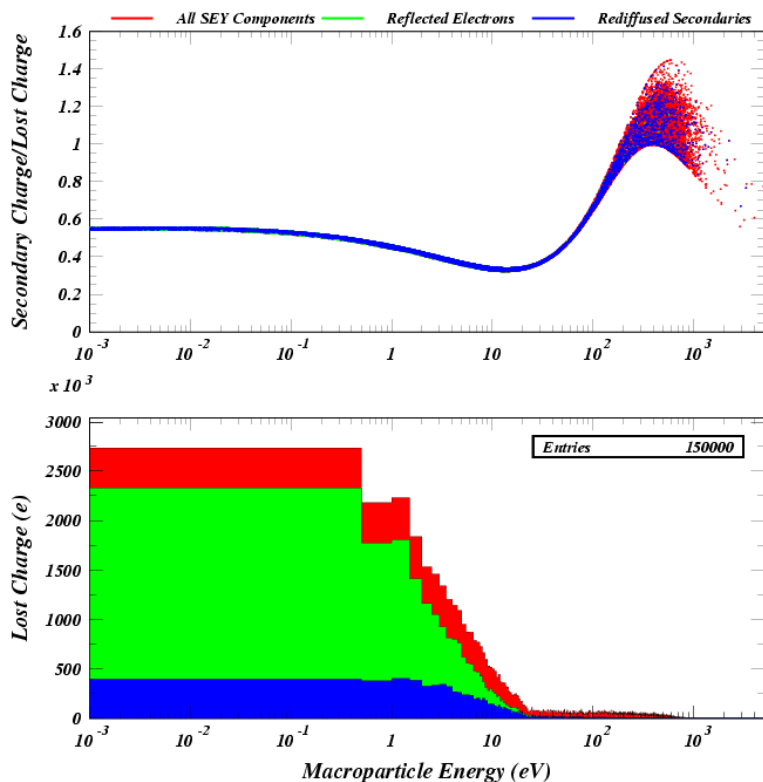


Secondary Yield Model

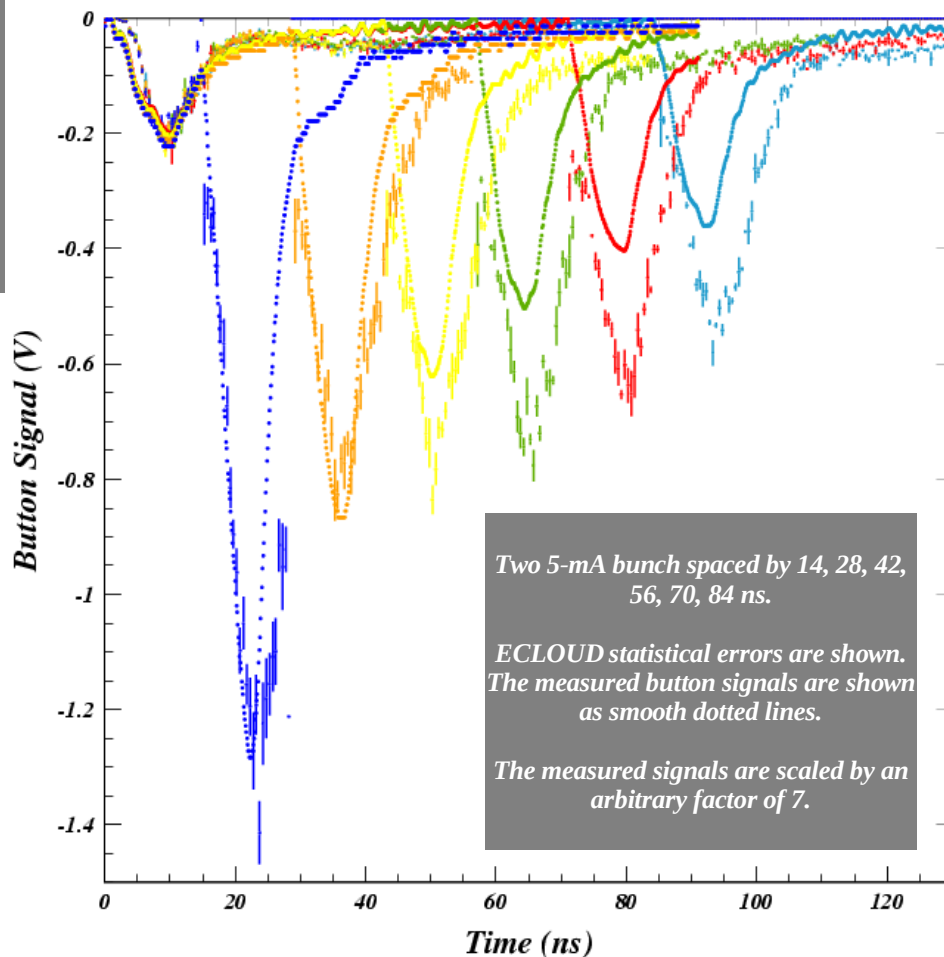
True secondary yield: 0.9
True secondary peak energy: 400 eV

Rediffused yield: 0.1

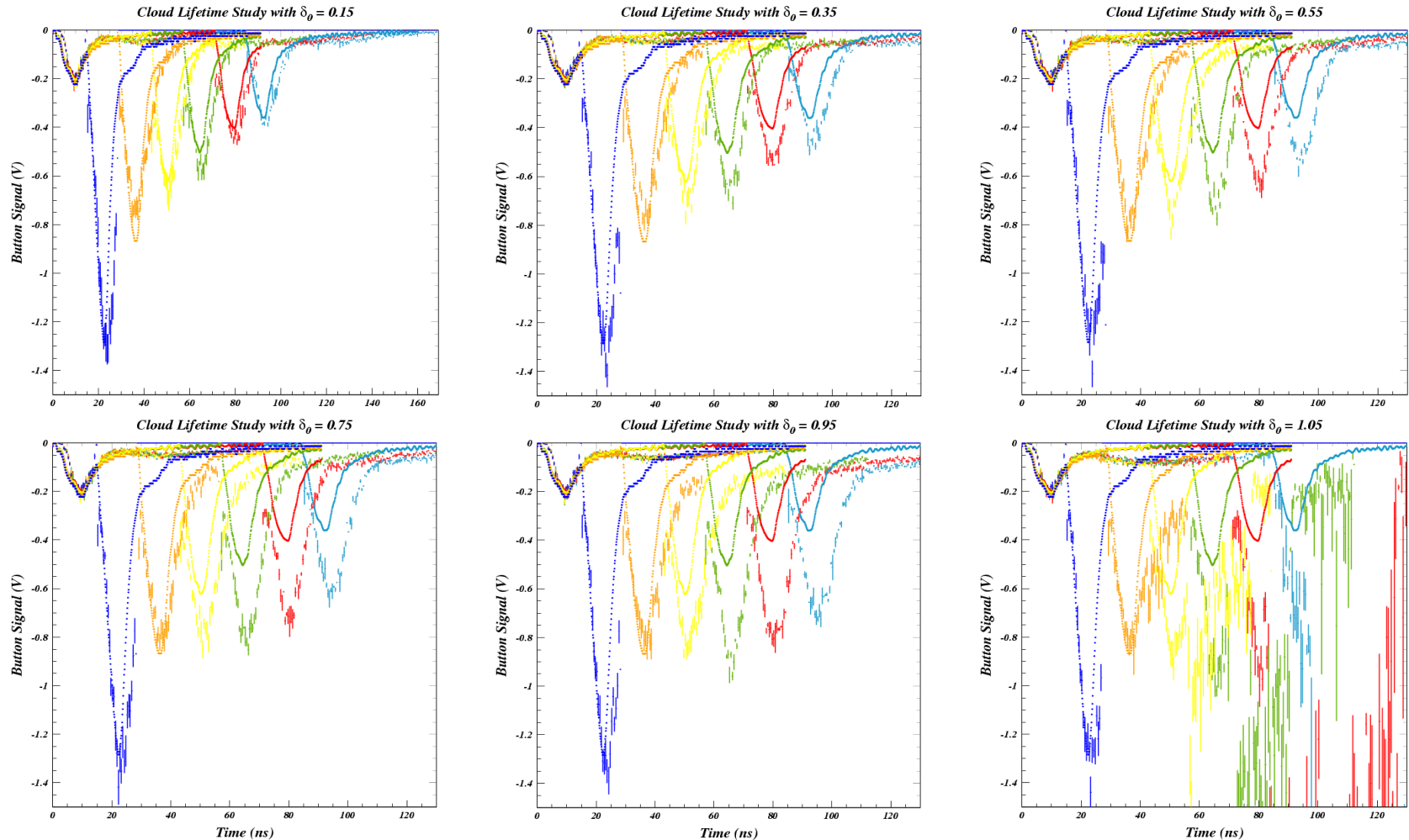
Elastic yield δ_0 : 0.55



Cloud Lifetime Study with $\delta_0 = 0.55$



Simulated cloud lifetime too long: reduce elastic yield?



The optimal value for δ_0 (0.15) is lower than has been generally assumed (0.5-0.7).

Note that not only the simulated peak signal value for witness bunch signals is better, but also the width.

Could such a low elastic yield be a characteristic of TiN coating?

Our tune shift simulations gave reasonable cloud decay times with a value of 0.5 for uncoated aluminum chambers.